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# An Analog Subsystem for the Plutonium Protection System

H. Duane Arlowe



Sandia Laboratories

2950 O(7-73)

# MASTER

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Printed December 1978

## AN ANALYSIS OF THE EFFECTS OF PULSED FIELD PROTECTION ON FIELD

By: D. J. S. JONES  
1973-0872-1-1  
Final post Release  
Printed December 1978

### ABSTRACT

The effects of pulsed field protection on the performance of a  
pulsed field protection system are investigated. The results of  
the analysis are compared with the results of a similar analysis  
of a continuous field protection system. The results show that  
the pulsed field protection system is more effective than the  
continuous field protection system. The results also show that  
the pulsed field protection system is more efficient than the  
continuous field protection system.

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## AN ANALOG SUBSYSTEM FOR THE PLUTONIUM PROTECTION SYSTEM

### Introduction

The Plutonium Protection System (PPS) is an item protection system that demonstrates advanced storage concepts which integrate detection and delay elements with careful monitoring and control of operational procedures. In addition, the accountability, operations, and security centers are physically separated to reduce vulnerability to insider threat. Organization of the PPS is illustrated in Figure 1. The five components of the PPS are interconnected with a data communications network:

- The Storage Vault is an Item Control Area (ICA) in which advanced detection and delay elements reduce the vulnerability to insider and to forced entry threats. Personnel access is carefully controlled and the three control centers continually interact to assure the proper movement of material.
- The Container Module Packaging (CMP) room is an ICA which provides point of entry to the PPS, i. e., material is packaged into standardized containers to prepare it for storage. For this demonstration, the CMP room is under the direct control of the Material Operations Center; in actual application, its structure would be similar to that of the vault, with access control and interaction among three control centers.
- The Material Operations Center (MOC) is a control center which monitors and controls all operations involving movement of items in the system.
- The Material Accountability Center (MAC) is a control center which maintains the accountability of all items in the system.
- The Security Operations Center (SOC) is a control center which monitors and responds to all alarms in the system and controls personnel access to the system.

Movement of material between the ICAs is accomplished in a secure fashion by means of a Secure Transport Module (STM) which is essentially a minivault on wheels. The STM must be securely docked at a port in the wall of the ICA before material can be loaded or unloaded. The actual transport of material is carefully timed to minimize the time available for tampering or diversion.

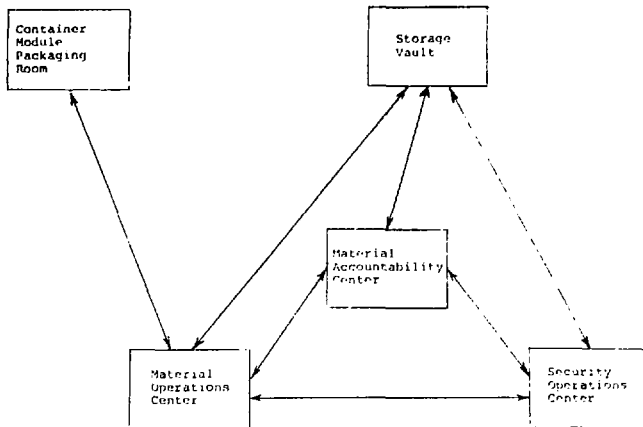


Figure 1. Plutonium Protection System Organization

The focal point of the PPS is the vault, which includes a personnel entry corridor, alarm and assessment components, a protected computer, and a storage room that contains Secure Storage Modules (SSM). The first three items carefully control access to the storage area, while the SSM provides physical barriers and alarms to detect any attempt to gain unauthorized access to the stored items once entry to the storage area is achieved. Figure 2 illustrates how the PPS has been set up in the Sandia Systems Integration Laboratory.

The SSM consists of four concrete cabinets, each housing a carousel containing 75 storage locations in seven layers of five positions each. The storage locations are staggered so that the door assembly limits access to one location at a time. Specially designed Container Modules (CMs) are used to house the stored plutonium metal or oxide. Each CM is instrumented with an electronics package that contains several analog sensors to monitor state-of-health such as temperature and the "bulge" of the inner can. The SSM also contains rotary potentiometers which monitor the position of the carousels. These analog signals must be digitized to be compatible with the microprocessor-based SSM controller.

The Analog Subsystem discussed in this report accomplishes the signal conditioning required so that the analog outputs are compatible with the SSM controller. The controller in the CMP room and the controller for the vault dock utilize the Analog Subsystem to monitor the rotary position of the STM carousel as well as the sensors in the Container Modules. In the CMP room the weight of the CM is determined by a linear potentiometer (coupled with a spring) that must be conditioned by the Analog Subsystem.

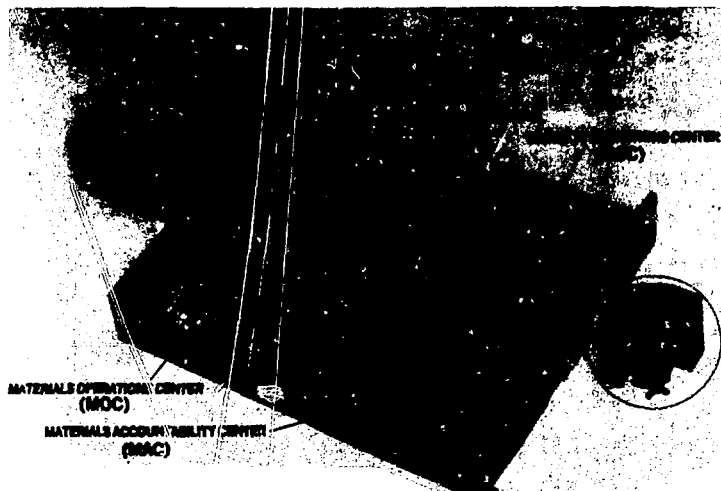


Figure 2. Plutonium Protection System/Systems Integration Laboratory

#### Summary

Several analog sensors are used in the Plutonium Protection System; those that interface with one of the microcomputer-based controllers must first have their outputs digitized. Signal conditioning as provided for the following measurements:

- Two temperature monitors in the Container Module (CM)
- A reading of the "badge" of the inner can in the CM
- The rotary positions of the carousels in the Secure Storage Module (SSM)
- The rotary position of the carousel in the Secure Transport Module (STM)
- The weight of the CM as measured in the CIP room.

The Analog Subsystem provides the signal conditioning required by the analog sensors. The subsystem utilizes an analog multiplexer (MUX) and an Analog-to-Digital Converter (ADC) to convert these analog signals to eight-bit digital words suitable for the microcomputer controllers.

The analog inputs are divided into direct and indirect channels. The direct channels monitor a single sensor such as the position of each carousel in the SSM, the carousel in the STM, and the spring-balance in the CMP room. These sensors are potentiometers powered by +5 and -5 volt<sup>2</sup> references, whose outputs go directly to the analog MUX. The indirect channels monitor the sensors in each CM. Because of the large number of sensors involved, a "CM selection" scheme is used which activates only the CM of interest, even though as many as 35 monitors may be connected to a single input of the Analog Subsystem. The indirect channels are buffered by current summing amplifiers before going to the analog MUX.

### System Description

The Analog Subsystem uses an Analog Multiplexer (MUX) and an Analog-to-Digital Converter (ADC) to convert analog inputs to eight-bit digital words suitable for the microcomputer controllers<sup>1</sup> in the PPS. The term ADC/MUX is commonly used when referring to the Analog Subsystem. This subsystem is used in three distinct applications:

- In the SSM, analog signals from the rotary potentiometer<sup>2</sup> on the carrouseils, and the state-of-health monitors in the containers<sup>3</sup> are digitized by the ADC/MUX. This unit is located on the far right-hand end of the electronics enclosure, when viewed from the front.
- In the vault portal controller the sensors in the CMs are monitored as well as the position of the STM carousel.<sup>4</sup> This unit is located in the vault control room in the controller marked "STM Controller."
- In the CMP room the same sensors are monitored as in the vault portal controller, with the addition of the spring-balance potentiometer<sup>5</sup> that weighs the CM. This unit is located in the rack chassis marked "CMP Controller."

Figure 3 illustrates the layout of the SSM Analog Subsystem. Each block shown represents a plug-in printed circuit (PC) card. These four cards plug into a small black anodized aluminum heat sink chassis which all system diagrams have labeled ADC/MUX (sometimes chassis C). The 16-channel input multiplexer card, and the ADC card are commercially available from Phoenix Data, and the current-to-voltage converter card and the power supply card are made at Sandia. Appendix A contains all pertinent schematics and data sheets.

An 11-bit, two's complement, binary ADC was selected for this prototype system in case an 8-bit word proved to have insufficient resolution. The 8-bit capability has been found to be quite adequate for all analog measurements as currently utilized, and system accuracy is limited more by system power supply voltages and mechanical couplings, especially in regards to carousel rotational position.

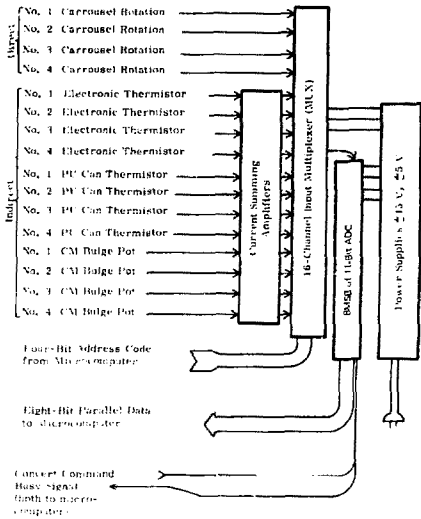


Figure 3  
SSM Analog Subsystem

The ADC/MUX systems operate in a similar manner regardless of where they are used. The system in the SSM monitors sensors (Figure 3). The Vault Port Controller and the CMP Room Controller use the ADC/MUX system to monitor STM rotation and/or CM weight rather than SSM carousel rotation (Figure 4). In each system, input signals can be divided into direct and indirect channels (Figures 3 and 4).

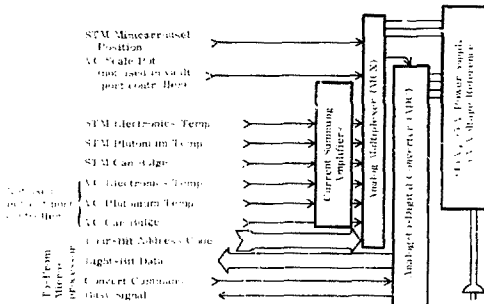


Figure 4. Vault Port and CMP Room Analog Subsystem



### Direct Channels

Direct channels monitor only a single sensor such as the position of each carousel in the SSM, the carousel in the STM, and the detector of the spring-balance weighing scale in the Verification Chamber (VC). In every case, the transducer is a potentiometer powered by -5 and +5-volt reference voltages on the ADC/MUX power supply card. These voltages may be monitored at pin jacks on the front of the chassis.

These channels are direct because there is no signal conditioning or additional multiplexing between the signal source (potentiometer) and the analog MUX card in the system. The microprocessor needs only to address the proper input channel, send a convert command, and then wait for the busy line to go low before taking a reading.

### Indirect Channels

The remaining channels monitor temperatures (thermistors) and food-pack can bulging (linear potentiometer) inside the CMs. A multiplexing scheme is used which takes advantage of the fact that most of the electronics in each CM are turned off until interrogated by the PPS.

Figure 5 shows how the variable resistance sensors are used to feed signal current into the common summing point of the ADC/MUX input amplifiers.

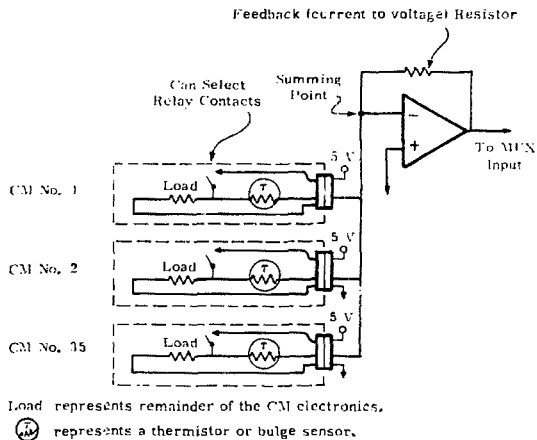


Figure 5. Variable Resistance Sensors

The concept of the scheme is simple. When a CM is interrogated, the relay contacts on the selected CM close, applying voltage to both the digital electronics and the sensor(s) inside the CM. A signal current, inversely proportional to the sensor resistance, then flows through the carousel cabling to the op-amp summing junction. The op-amp outputs a voltage to the feedback resistor so as to keep the summing point near zero volts. The current from the sensor is then converted to an output voltage across the feedback resistor.

This concept assumes that only one CM in each carousel will be selected for interrogation at one time. The other 34 CMs will be off so that the voltage across their sensors will be near zero and they will contribute little or no current to the summing junction, regardless of their resistance.

Because of leakage currents, ground loops, and millivolt drops due to power currents flowing in common ground returns, there will be noticeable errors generated as a result of this technique. However, the information needed does not require high precision and these add-on analog measurements have been included for very small per-unit costs (~\$10.00) per CM. The main purpose of these indirect measurements is to warn the system if:

- The electronics is becoming hot enough to fail
- The plutonium can seal is approaching its integrity temperature
- The plutonium can starts to bulge
- There is no longer any heat flow out of the CM, indicating that the radioactive material is gone.

This last measurement has a time lag of one-half hour or so and is not a fast tamper indicator.

Drawing CK-T42789 in Appendix A shows how the indirect measurements come straight to this card through a flat ribbon cable on connector CP4 (P4 on chassis C). The op-amps are labeled U-1 to U-12. The feedback and input bias resistors have been selected to give the desired output voltage. The thermistors have a nonlinear negative temperature coefficient; the data are listed in Table B-1 of Appendix B. A 2200-ohm resistor has been placed in series with each thermistor to make the current more proportional to temperature over the range of interest (25° to 130°C). The resulting voltage out is also in Appendix B.

The feedback resistor on each op-amp is by-passed by a capacitor to provide a low pass-filter function with a -3 dB frequency of about 1000 Hz. This filter action reduces high frequency noise, especially clock noise from the microprocessor. A lower cutoff frequency would cause excessive settling time when a CM is selected during inventory.

One important step inherent in this current-summing scheme is to assure that the reference ground for the noninverting op-amp input is as close as possible to the potential of the power connection to the unselected CMs. Whatever voltage difference exists will contribute to small but cumulative inputs from the sensors in those CMs.

This problem has been minimized by providing one bus wire labeled ANALOG RETURN to each carousel. This wire carries no dc power current, so it experiences no IR drop. By being connected to each of the seven carousel junction box grounds through a 51-ohm resistor, this analog return bus seeks a potential that is an average between the ground voltages at all seven levels. The result will be an averaging of the positive and negative ground loop biases, and a considerable cancellation of error. The analog ground return comes back separately from each carousel to the noninverting inputs of the three corresponding op-amps. A series resistor helps balance the effects of input bias currents.

In some installations that use longer cables, such as the unibittical cable in the vault STM port controller, small signals from the summing junction apparently couple over to the noninverting input, causing an oscillation of several hundred kilohertz. Therefore, 0.022-microfarad bypass capacitors have been added to the positive input of each op-amp.

#### Troubleshooting

The repair philosophy of this chassis calls for field replacement rather than field repair. The troubleshooting approach will depend on the PPS status at the time, but, in any case, every effort should be made to confirm that the trouble lies in this chassis and not elsewhere. This may save a trip into the vault and may obviate opening the electronic enclosure.

#### Computer System Up and Running (Vault ICA or MOC)

The fact that the same ADC/MUX not only rotates the carrouseles but also senses the CM detectors can provide a major clue. If all can measurements are correct, but the carousel does not turn properly, the ADC or MUX cards are probably not at fault. Check for presence of  $\pm 5$  volts on the front of the ADC/MUX chassis. If some carrouseles turn properly but others not, a check should be made for bad rotary potentiometers or cables, or defective MUX address-bits from the microprocessor. When carrouseles turn well, but some or all analog CM channels give bad readings, the analog board needs replacing.

If any of the above steps indicate that the problem may lie in this chassis, and time or radiation exposure is a problem, the most expedient solution is to replace the whole chassis. If conditions allow, replacing individual boards will save time later on, but the power supply voltages should be checked to see if they are proper before replacing other cards.

It is important to remember that all active components are mounted on the set of four cards, and it is extremely unlikely that any internal wiring will fail. To replace the boards, turn off power to the chassis and fan. Remove fan assembly, and flat ribbon connectors and slide the cards out.

WARNING:

Cards are not keyed and if they are plugged into the wrong slot or inserted upsidedown, damage will result. Figure 6 illustrates proper location and orientation.

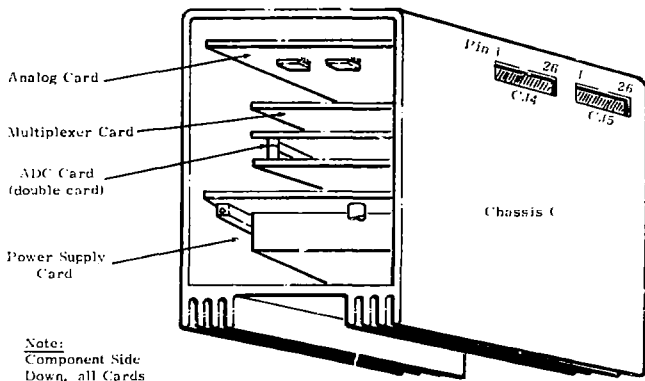


Figure 6. Location and Orientation of PC Cards

Computers Down or Not Available

A special ADC/MUX tester allows stand-alone testing of this chassis. Remove all existing cables except for the power cord. Connect the tester cables according to the labels. Check for polarity on the flat ribbon cables since they are not keyed. To check a particular channel, toggle the four binary switches to get the desired MUX address as displayed on the tester. Press the CONVERT command button. The reading obtained should be within  $\pm 1$  bit of the value printed on the table attached to the tester. As before, if addresses C, D, E, F check out alright, but some or all of the remaining 12 channels do not, the problem lies in the analog card. If none of the channels test correctly, the problem is in the commercial cards or in the power supply. The power supply should be checked with a voltmeter. The 15-volt supplies may vary  $\pm 0.5$  volt and the  $\pm 5$ -volt jacks should each measure  $4.985 \pm 0.015$  volts after a 15-minute warmup.

If the negative 5-volt output does not track the positive 5-volt supply, adjust the trimmer pot on the power supply board by removing the back cover and fan.

If any of the power supply modules are burned out, they may be replaced by removing the two 4-40 mounting screws from the PC board.

#### Replaceable Parts

Nonfunctioning parts should be returned to Sandia Laboratories in Albuquerque for repair; the following components may be replaced with spare parts:

- The entire unit may be replaced with a spare
- Each of four individual cards may be replaced with those from the chassis in the spare unit
- The power-supply modules on the power-supply card may be replaced individually but these are not stocked by Sandia.

#### References

1. Leslie H. Minnear, A Family of Digital Controllers for the Plutonium Protection System, SAND78-0384 (Albuquerque: Sandia Laboratories, 1978).
2. H. Duane Arlowe, Wiring for the Secure Storage Module for the Plutonium Protection System, SAND78-0699 (Albuquerque: Sandia Laboratories, 1978).
3. H. Duane Arlowe and R. S. Howard, A Special Nuclear Material Container Module for the Plutonium Protection System, SAND78-0695 (Albuquerque: Sandia Laboratories, 1978).
4. H. Duane Arlowe, Wiring for the Secure Transport Module and Vault Dock for the Plutonium Protection System, SAND78-0690 (Albuquerque: Sandia Laboratories, 1978).
5. H. Duane Arlowe, Wiring for the CMP Room and Verification Chamber for the Plutonium Protection System, SAND78-0694 (Albuquerque: Sandia Laboratories, 1978).

APPENDIX A  
Schematic Diagrams

APPENDIX A  
Schematic Diagrams

# ECONOMY

## ANALOG TO DIGITAL CONVERTERS\*

### ADC 400 Series

**HIGH SPEED CONVERSION**

15 MHz for 14-bit  
4 MHz for 12-bit  
8 MHz for 10-bit

**ACCURACY**

0.01% of Full Range (ADC 410)

**ECONOMY**

14-Bit for \$345

**VERSATILITY**

Binary, Par Compatability, Non-Standard Input Ranges,  
Non-Standard Input Voltages, etc.

**SELF-CONTAINED**

Including Precision Reference Voltage

**REPAIRABLE**

No Polled Active Circuits

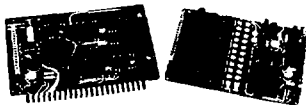
#### GENERAL DESCRIPTION

The ADC 400 Series Analog to Digital Converters are designed to provide an exceptional price/performance ratio. The technique of voltage switching successive approximation is utilized to provide very fast, accurate conversion, with excellent repeatability, linearity, and monotonicity.

An ADC 400 Series Converter is a complete, fully assembled, tested, and calibrated, system ready plug-in module. It incorporates all the functions necessary to perform the conversion except for the power supplies. No external reference voltage source, amplifiers, or transmuting potentiometers are required.

Each ADC 400 Series Converter is a complete functional unit. The accuracy and temperature coefficient specifications can be used, and do include the errors due to the analog switches, the internal reference voltage generator, comparator offset, gain error, non-linearity, calibration resolution, resistor network tracking, quantizing error, and power supply variations within  $\pm 5\%$  tolerance.

The ADC 400 units are available in 8 thru 14 bit binary configurations, with four input voltage ranges offered as standard. Options offered include a high speed, high input impedance buffer amplifier, and units with an extended operating temperature range.



#### OPTIONS AVAILABLE

High Input Impedance Buffer Amplifier  
Extended Operating Temperature Range of  $-55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$   
Special Input Voltage Ranges  
Package size can be extended to suit particular applications.

\*Reprinted from brochure issued by

**PHOENIX DATA, INC.**  
3304 WEST OSBORN ROAD - PHOENIX, ARIZONA 85017 •

## FUNCTIONAL DESCRIPTION ADC400 SERIES

The ADC400 Series Analog-to-Digital Converter (ADC) provides a high resolution digital output for a wide range of applications. The ADC400 Series is available in 8, 12, 14, and 16 bit versions. The ADC400 Series is a single channel, single ended, unipolar, parallel output, CMOS compatible, 100 kHz reference voltage, precision, single supply, precision resistor network, and single supply type. The output is completely digital and is independent of the input signal.

The ADC400 Series is available in 8, 12, 14, and 16 bit versions. The ADC400 Series is a single channel, single ended, unipolar, parallel output, CMOS compatible, 100 kHz reference voltage, precision, single supply, precision resistor network, and single supply type. The output is completely digital and is independent of the input signal.

The ADC400 Series is available in 8, 12, 14, and 16 bit versions. The ADC400 Series is a single channel, single ended, unipolar, parallel output, CMOS compatible, 100 kHz reference voltage, precision, single supply, precision resistor network, and single supply type. The output is completely digital and is independent of the input signal.

## SPECIFICATIONS

MODEL	ADC400	ADC401	ADC402	ADC403	ADC404	ADC405	ADC406
Resolution	8 bits	12 bits	12 bits	14 bits	14 bits	16 bits	16 bits
Input Range	12 VPP, 0 to 12V						
Input Impedance	10 <sup>10</sup> Ω						
Conversion Time	100 ns	100 ns	100 ns	100 ns	100 ns	100 ns	100 ns

Note: 1. See Figure 1 for pin connections. 2. Input Impedance is 10<sup>10</sup> Ω. 3. Conversion Time is 100 ns.

### ANALOG INPUT SIGNALS

Input Range: 0 to 12V  
Input Impedance: 10<sup>10</sup> Ω  
Input Signal: 0 to 12V  
Input Impedance: 10<sup>10</sup> Ω  
Input Signal: 0 to 12V  
Input Impedance: 10<sup>10</sup> Ω

### CONTROL SIGNALS AND DELAYS

Input Delay: 2 ns  
Input Delay: 2 ns  
Input Delay: 2 ns  
Input Delay: 2 ns  
Input Delay: 2 ns  
Input Delay: 2 ns  
Input Delay: 2 ns  
Input Delay: 2 ns  
Input Delay: 2 ns  
Input Delay: 2 ns

Pin 1  
Pin 2

### POWER REQUIREMENTS

Supply Voltage: 5V  
Supply Current: 100 μA  
Supply Current: 100 μA  
Supply Current: 100 μA

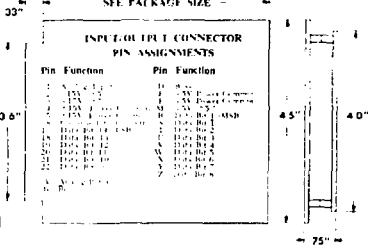
### ENVIRONMENTAL

Temperature: 0 to 70°C  
Operating: 0 to 70°C  
Storage: -55 to 150°C  
Humidity: 10 to 90% Relative Humidity  
Non-condensing

PACK SIZE (8, 12, 14 bits) 4-pin DIP

PACK SIZE (16 bits) 4-pin DIP

### SEE PACKAGE SIZE



Model ADL + A-95

### ORDERING INFORMATION

ADC4XX	X	X	XX	XX
08	8 bits		Block	0 to 70°C
09	9 bits		Block	0 to 70°C
10	10 bits		Block	0 to 70°C
11	11 bits		Block	0 to 70°C
12	12 bits		Block	0 to 70°C
13	13 bits		Block	0 to 70°C
14	14 bits		Block	0 to 70°C
			R	Input Amp
			I	Input Amp

A Input Amp  
Block No Input Amp

LOCAL REPRESENTATIVE



## GENERAL DESCRIPTION:

The MX 1670 is an easy-to-use, 16-channel multiplexer providing high-speed, very accurate analog signal switching. The unit is divided into two eight-input switching sections. Each switching section has 8 binary-coded address lines and an inhibit line. Decoding drive circuitry, MOSFET switching, and optional buffer amplifiers and oversvoltage protection are all included on the card which inserts into an Ekin 6022 or X-Ang 25H22 edgeboard connector.

A complete 128-channel analog commutator may be readily constructed by using additional MX 1670's and a PDI Model 14000 Multiplexer Control Card.

The optional buffer amplifiers can be specified as to gain (up to a gain of ten) by the user to achieve the desired voltage range at the output of the multiplexer.



## ADDRESSING

### Eight Channel Differential Operation

Switching 8 pairs of inputs to the decoder with A0, A1, A2, A3, A4, A5, A6, and A7 as 8B and 8A as 8A; A8, A9, A10, A11, A12, A13, A14, and A15 as 8B.

### sixteen Channel Operation

As above, with the parity 8 output to the MX 1670 is connected to A0 input and the 8 output connected to the B0 input.

## MUX 1670

### FEATURES

#### ACCURACY

- No Offset Voltage
- Low Leakage (Typically 2 nA)
- Low Crosstalk (Typically 0.1% of Range Max)

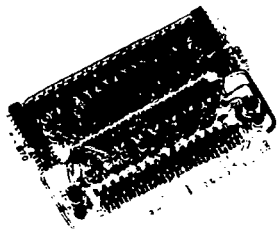
#### LINE

- Up to 200K channels at 1ms

#### CONSTRUCTION

- Plugs into Standard Edgeboard Connectors
- Fully Tested
- Completely Repairable
- Easily Reproducible

#### OPTIONAL BUFFER AMPLIFIERS



## ORDERING INFORMATION

MUX 1670 - 08 for 8-VA Input

MUX 1670 - 16 for 16-VA Input

Options Must Be Stated

## SPECIFICATIONS

### ANALOG INPUTS

Number of Analog Inputs	16 Single ended or 8 differential
Input Voltage Range	±10V (with ±15V and 20 to 24V Supplies) ±5V (With ±15V Supplies)
Input Overvoltage	±15V Max. any input
Input Capacitance	Less than 200 pF (worst case)
Off Impedance	Greater than 100 megohms
Off Input Current (25°C)	Less than 1nA
Crosstalk (K <sub>c</sub> )	Less than ±0.01% of full range for ±10V input with other 7 as polys driven ±10V at 1kHz
On Resistance (R <sub>on</sub> ) (psd)	300 Ohms Maximum
On Input Current (25°C, Output Open)	Less than 5 nA
Settling Time (R <sub>s</sub> ) (K <sub>s</sub> )	5 Microseconds to ±0.01% of final value

### COMMON INPUTS

Logic Levels	
Logic 1 Voltage	+2.4V to +5.0V
Logic 1 Current	40 Microamperes
Logic 0 Voltage	0V to +0.4V
Logic 0 Sink Current	15 Milliamperes
Address Inputs	1 Line for each 8 input switching Binary Code 04-2-11 1 Line for each 8 input switching 1 Line, 1 Level inhibits all 8 switches regardless of address in bits

### POWER REQUIREMENTS

Logic Supply	+5 volts, 5%, 60 ma nominal
V <sub>cc</sub> Supply	+15 volts, ±5%, 10 ma nominal
V <sub>ee</sub> Supply	-15 volts. Max. line switching ±3 volts, 450 mA nominal 25 volts Max. line switching 10 volt levels, 40 mA nominal

### ENVIRONMENTAL

Temperature (Extended Ambient)	
Operating	+6°C to +70°C
Storage	-55°C to +250°C
Humidity	1 to 95% relative noncondensing

## APPLICATIONS

Time Division Multiplex (Time Share) of many analog voltage input signals into a single output device such as an analog signal sample and hold and/or analog to digital converter.

Time Division Multiplex (Data Distribution) of a single input signal to many output devices such as analog holding circuits, recorder channels, et cetera

Single Selection of multiple gain determining circuits around or within an instrumentation amplifier

Other applications which require the selection and connector of precision analog voltage at high rates

## OPTIONS AVAILABLE

Overvoltage Protection (No Additional Price)

Increases Input Overvoltage to ±10V, Maximum

Increases On Resistance to 2.5K Ohms

Increases Input Leakage Current to 25 nA, Maximum

Increases Settling Time

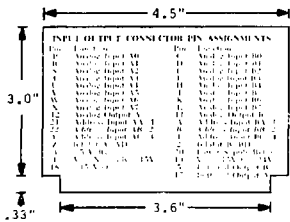
Buffer Amplifiers (one per eight switches)  
Customer must specify characteristics of amplifiers (gain, input impedance, et cetera)

Hermetically Sealed Active Components

Extended Operating Temperature Range

55°C to +125°C

### PACKAGE CONFIGURATION



## LOCAL REPRESENTATIVE

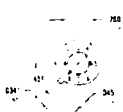
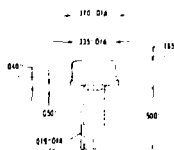
Nov. 1971

# SPECIFICATIONS

MODEL 3500 A, B, C, D	MODEL 3500 E, F	MODEL 3500 G, H	MODEL 3500 I, J	MODEL 3500 K, L	MODEL 3500 M, N	MODEL 3500 O, P
<b>OPEN LOOP GAIN</b>						
<b>RATED OUTPUT</b>						
<b>FREQUENCY RESPONSE</b>						
<b>INPUT OFFSET VOLTAGE</b>						
<b>INPUT BIAS CURRENT</b>						
<b>INPUT DIFFERENCE CURRENT</b>						
<b>INPUT IMPEDANCE</b>						
<b>INPUT NOISE</b>						
<b>INPUT VOLTAGE RANGE</b>						
<b>POWER SUPPLY</b>						
<b>TEMPERATURE RANGE</b>						

## TO 99 PACKAGE

Specify 3500A, etc



BOTTOM VIEW

## MINI-DIP PACKAGE

Specify 3500A-N, etc



TOP VIEW

Dimple appears over pin space \*

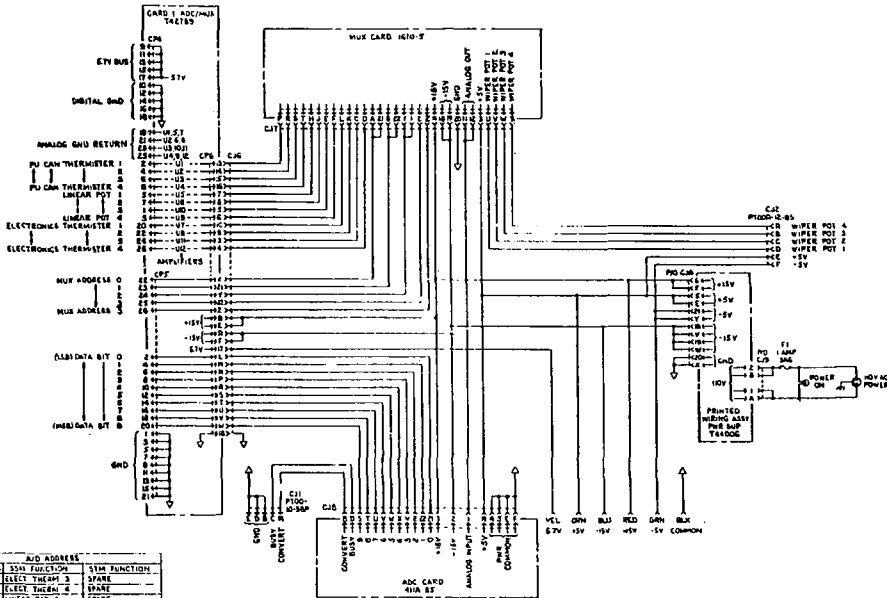


Note: Dimensions in millimeters are shown in parentheses.

## PIN CONNECTIONS

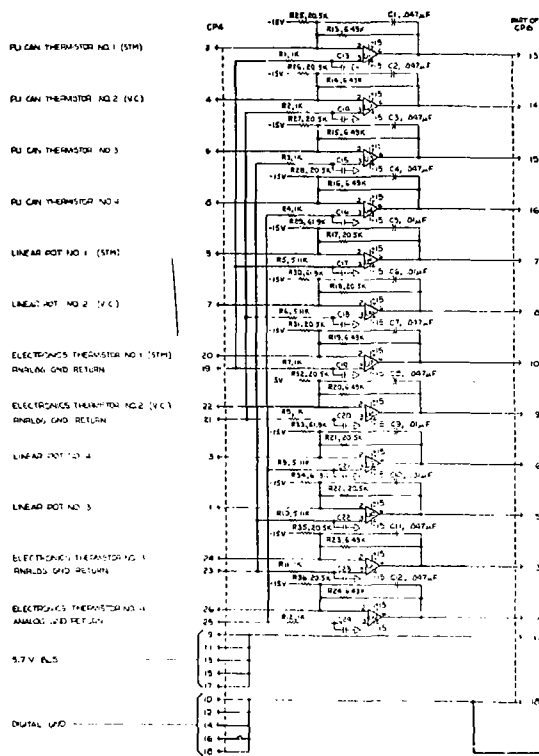
1-IN	5-NC
2-IN	6-CL INPUT
3-IN	7-V-
4-V-	8-NC

\*Pin 4 is connected to the case on the TO-99 package.

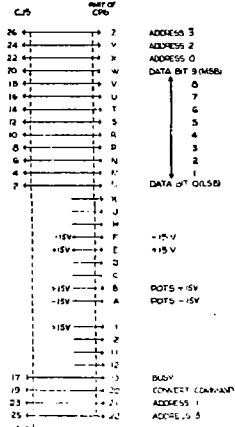


ADC ADDRESS	SW FUNCTION	SW FUNCTION
0000	ELECT THERM 1	SPARE
0001	ELECT THERM 2	SPARE
0002	LINEAR POT 1	SPARE
0003	LINEAR POT 2	SPARE
0004	LINEAR POT 3	LINEAR POT 5TH
0005	LINEAR POT 4	LINEAR POT 1E
0006	ELECT THERM 3	ELECT THERM 1C
0007	ELECT THERM 4	ELECT THERM 2TH
0008	PU CAN THERM 1	PU CAN THERM 5TH
0009	PU CAN THERM 2	PU CAN THERM 1C
0010	PU CAN THERM 3	SPARE
0011	PU CAN THERM 4	SPARE
0012	POT WIPER 1	POT WIPER 5TH
0013	WGT	WGT WEIGHT POT
0014	POT WIPER 2	SPARE
0015	POT WIPER 3	SPARE
0016	POT WIPER 4	SPARE

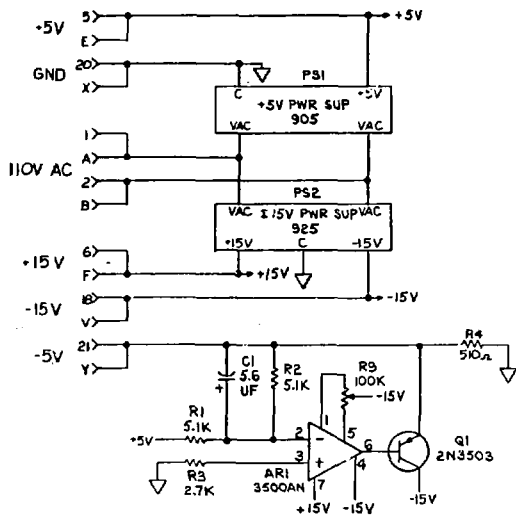
Drawing No. CK-T42560 - ADC/MUX



- NOTES**
1. C1-C4 ARE 047uF
  2. ALL RESISTORS ARE 0.1WATT 1/25W WETA. FILM.
  3. CPU PINS 1500IN (BUBBLE-POINT)



Drawing No. CK-T42789 - Analog Card, ADC/MUX



Drawing No. CK-T44006 - Power Supply

APPENDIX B  
Conversion Tables

APPENDIX B  
Conversion Tables

The analog subsystem components have been designed to yield the following digital output for the temperature values shown. These values have been confirmed experimentally when there is 5.8 volts applied to the power connections to the Container Module.

TABLE B-1  
Temperature Conversion

Decimal	$P_T/R_{25}$	Temp (°C)	Hex	Decimal	$P_T/R_{25}$	Temp (°C)	Hex
-128	0.038	120	80	-104	0.049	111	98
-127	0.038	120	81	-103	0.050	110	99
-126	0.038	120	82	-102	0.050	110	9A
-125	0.039	119	83	-101	0.051	110	9B
-124	0.039	119	84	-100	0.052	109	9C
-123	0.040	119	85	-99	0.052	109	9D
-122	0.040	119	86	-98	0.053	109	9E
-121	0.041	118	87	-97	0.053	109	9F
-120	0.041	118	88	-96	0.054	108	A0
-119	0.042	117	89	-95	0.054	108	A1
-118	0.042	117	8A	-94	0.055	107	A2
-117	0.043	116	8B	-93	0.056	107	A3
-116	0.043	116	8C	-92	0.056	107	A4
-115	0.044	115	8D	-91	0.057	106	A5
-114	0.044	115	8E	-90	0.057	106	A6
-113	0.045	114	8F	-89	0.058	105	A7
-112	0.045	114	90	-88	0.059	104	A8
-111	0.046	114	91	-87	0.059	104	A9
-110	0.046	114	92	-86	0.060	104	AA
-109	0.047	113	93	-85	0.061	104	AB
-108	0.047	113	94	-84	0.061	104	AC
-107	0.048	112	95	-83	0.062	103	AD
-106	0.048	112	96	-82	0.063	103	AE
-105	0.049	111	97	-81	0.063	103	AF



TABLE B-1 (cont)

Decimal	$R_T/R_{T_{25}}$	Temp (°C)	Hex	Decimal	$R_T/R_{T_{25}}$	Temp (°C)	Hex
-80	0.064	102	B0	-43	0.095	89	D5
-79	0.065	101	B1	-42	0.096	88	D6
-78	0.065	101	B2	-41	0.097	88	D7
-77	0.066	101	B3	-40	0.098	88	D8
-76	0.067	100	B4	-39	0.099	87	D9
-75	0.067	100	B5	-38	0.100	87	DA
-74	0.068	100	B6	-37	0.101	87	DB
-73	0.069	99	B7	-36	0.102	86	DC
-72	0.070	99	B8	-35	0.103	86	DD
-71	0.070	99	B9	-34	0.105	86	DE
-70	0.071	98	BA	-33	0.106	85	DF
-69	0.072	98	BB	-32	0.107	85	E0
-68	0.072	97	BC	-31	0.108	85	E1
-67	0.073	97	BD	-30	0.109	84	E2
-66	0.074	97	BE	-29	0.110	84	E3
-65	0.075	96	BF	-28	0.112	84	E4
-64	0.076	96	C0	-27	0.113	83	E5
-63	0.077	96	C1	-26	0.114	83	E6
-62	0.077	96	C2	-25	0.115	83	E7
-61	0.078	95	C3	-24	0.117	82	E8
-60	0.079	95	C4	-23	0.118	82	E9
-59	0.080	94	C5	-22	0.119	82	EA
-58	0.081	94	C6	-21	0.121	81	EB
-57	0.082	94	C7	-20	0.122	81	EC
-56	0.082	94	C8	-19	0.124	80	ED
-55	0.083	93	C9	-18	0.125	80	EE
-54	0.084	93	CA	-17	0.126	80	EF
-53	0.085	92	CB	-16	0.128	79	F0
-52	0.086	92	CC	-15	0.129	79	F1
-51	0.087	92	CD	-14	0.131	79	F2
-50	0.088	91	CE	-13	0.132	78	F3
-49	0.089	91	CF	-12	0.134	78	F4
-48	0.090	90	D0	-11	0.135	78	F5
-47	0.091	90	D1	-10	0.137	77	F6
-46	0.092	90	D2	-9	0.139	77	F7
-45	0.093	89	D3	-8	0.140	77	F8
-44	0.094	89	D4				

TABLE B-1 (cont)

Decimal	$R_T/R_{25}$	Temp (°C)	Hex	Decimal	$R_T/R_{25}$	Temp (°C)	Hex
-7	0.142	76	F9	30	0.229	62	1E
-6	0.144	76	FA	31	0.232	62	1F
-5	0.145	75	FB	32	0.236	61	20
-4	0.147	75	FC	33	0.239	61	21
-3	0.149	75	FD	34	0.243	61	22
-2	0.151	74	FE	35	0.246	60	23
-1	0.152	74	FF	36	0.250	60	24
0	0.154	74	00	37	0.254	59	25
1	0.156	73	01	38	0.258	59	26
2	0.158	73	02	39	0.262	59	27
3	0.160	73	03	40	0.266	58	28
4	0.162	72	04	41	0.270	58	29
5	0.164	72	05	42	0.275	57	2A
6	0.166	71	06	43	0.279	57	2B
7	0.168	71	07	44	0.284	56	2C
8	0.170	71	08	45	0.288	56	2D
9	0.173	70	09	46	0.293	55	2E
10	0.175	70	0A	47	0.298	55	2F
11	0.177	70	0B	48	0.303	55	30
12	0.179	69	0C	49	0.308	54	31
13	0.182	69	0D	50	0.314	54	32
14	0.184	68	0E	51	0.319	53	33
15	0.186	68	0F	52	0.325	53	34
16	0.189	68	10	53	0.331	52	35
17	0.191	67	11	54	0.337	52	36
18	0.194	67	12	55	0.343	51	37
19	0.197	67	13	56	0.349	51	38
20	0.199	66	14	57	0.355	50	39
21	0.202	66	15	58	0.362	50	3A
22	0.205	65	16	59	0.369	49	3B
23	0.208	65	17	60	0.375	49	3C
24	0.210	65	18	61	0.384	48	3D
25	0.213	64	19	62	0.392	48	3E
26	0.216	64	1A	63	0.400	47	3F
27	0.219	64	1B	64	0.408	47	40
28	0.223	63	1C	65	0.416	46	41
29	0.226	63	1D	66	0.425	46	42

TABLE B-1 (cont)

Decimal	$R_T/R_{25}$	Temp ( $^{\circ}$ C)	Hex	Decimal	$R_T/R_{25}$	Temp ( $^{\circ}$ C)	Hex
67	0.434	45	43	104	1.511	16	68
68	0.444	44	44	105	1.607	14	69
69	0.454	44	45	106	1.716	13	6A
70	0.464	43	46	107	1.840	12	6B
71	0.475	43	47	108	1.982	10	6C
72	0.486	42	48	109	2.147	8	6D
73	0.497	42	49	110	2.341	7	6E
74	0.509	41	4A	111	2.572	5	6F
75	0.522	40	4B	112	2.851	3	70
76	0.535	40	4C	113	3.197	0	71
77	0.549	39	4D	114	3.636		72
78	0.563	39	4E				
79	0.578	38	4F				
80	0.594	37	50				
81	0.610	37	51				
82	0.627	36	52				
83	0.646	35	53				
84	0.665	34	54				
85	0.685	34	55				
86	0.707	33	56				
87	0.729	32	57				
88	0.753	32	58				
89	0.779	31	59				
90	0.806	30	5A				
91	0.835	29	5B				
92	0.865	28	5C				
93	0.898	27	5D				
94	0.934	27	5E				
95	0.972	26	5F				
96	1.013	25	60				
97	1.057	24	61				
98	1.106	23	62				
99	1.158	22	63				
100	1.215	21	64				
101	1.278	19	65				
102	1.348	18	66				
103	1.425	17	67				

TABLE B-2  
Bulge Sensor Conversion

Upper Deflection	$E_{in}$ $I_{in} \cdot Pot$ Wiper (volts)	$E_o$ Amplifier Output (volts)	Decimal	Hex (ADC)
0-1 mm	0.00	4.96	127	7F
2	0.38	4.18	107	6B
3	0.76	3.40	87	57
4	1.14	2.62	67	43
5	1.52	1.84	47	2F
6	1.90	1.06	27	1B
7	2.28	0.286	7	07
8	2.66	-0.49	-12	F4
9	3.04	-1.27	-32	ED
10	3.42	-2.05	-52	CC
11	3.81	-2.85	-73	B7
11.5	4.00	-3.24	-83	AD

Note:  $E_o = 4.96 - 2.05E_{in}$

TABLE B-3  
Verification Chamber Scale

$$\left( wt_{kg} = \frac{\text{reading}_{Dec} - 18}{13} \right)$$

Scale Tare (wt kg)	Decimal	Hex
	-4	FC
0	14	0E
0.5	20	14
1.0	27	1B
1.5	34	22
2.0	40	28
2.5	46	2E
3.0	53	35

TABLE B-4  
*(Carrousel ISTM) Rotation Conversion*

<u>STM Position</u>	<u>SSM Position</u>	<u>Pot Wiper (volts)</u>	<u>Decimal</u>	<u>Hex</u>
End	End	-5.00	-128	80
	1	-4.88	-125	83
1	2	-4.36	-112	90
	3	-3.85	-99	9D
Null	4	-3.33	-85	AB
	5	-2.82	-72	B8
2	6	-2.30	-59	C5
	7	-1.78	-46	D2
Null	8	-1.27	-33	DF
	9	-0.75	-19	ED
3	10	-0.24	-6	FA
	Null	0.02	0	00
	11	0.28	7	07
Null	12	0.79	20	14
	13	1.31	33	21
4	14	1.82	47	2F
	15	2.34	60	3C
Null	16	2.85	73	49
	17	3.37	86	56
5	18	3.88	98	62
	19	4.40	113	71
	20	4.91	126	7E
End	End	5.00	127	7F

TABLE B-5

## Resistance - Temperature Conversion

The following information may be used to test or calibrate the temperature channels in the SSM, STM, or Verification Chamber. The resistance values represent precision resistors commonly available at Sandia and correctly simulate the thermistor resistance plus 2200 ohms when 5.0 volts is applied to one side of the resistor and the other end of the resistor is connected to pin 1 (electronics temperature) or pin V (plutonium thermistor).

The current column is the resulting current that flows into the ADC/MUX amplifier summing junction when the simulator resistor is used with 5.0 volts impressed.

<u>Temp</u> <u>(°C)</u>	<u>R<sub>in</sub></u> <u>(k ohms)</u>	<u>Amplifier</u> <u>I<sub>in</sub> (mA)</u>	<u>V<sub>o</sub></u>	<u>Hex</u>
114	3.48	1.43	-4.53	89-8A
100	4.22	1.18	-2.9	B4-B5
86	5.36	0.932	-1.3	DE
70	7.50	0.666	0.42	0A-0B
50	12.7	0.393	2.20	39
29	27.4	0.182	3.56	5B
VC <sup>2</sup>		0	4.75	79

Very cold

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